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FORM PTO-1449

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT(S)

Atty Docket No. : 29273/502
 Serial No. :
 Inventors : H. KAWANO et al.
 Filed : 21 May 1999
 Group Art Unit :
 Examiner :

U.S. PATENT DOCUMENTS

Examiner Initial	Patent Number	Patent Date	Name	Class/ Subclass	Filing Date
<i>KF</i>	5,149,975	09/22/92	YODA et al.	250/492.2	
<i>KF</i>	5,278,421	01/11/94	YODA et al.	250/492.2	
<i>KF</i>	4,463,265	07/31/84	OWEN et al.	250/492.2	
<i>KF</i>	5,760,410	06/02/98	MATSUKI et al.	250/492.2	

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class/ Subclass	Translation Yes No
<i>KF</i>	3-225816	10/04/91	Japan		ABS.
<i>KF</i>	8-213315	08/20/96	Japan		ABS.
<i>KF</i>	10-229047	08/25/98	Japan		ABS.
<i>KF</i>	62-046059	09/30/87	Japan		ABS.
<i>KF</i>	63-014866	04/01/88	Japan		ABS.
<i>KF</i>	5-160010	06/25/93	Japan		ABS.
<i>KF</i>	9-293670	11/11/97	Japan		ABS.

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

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1. Murai et al.: *Fast proximity effect correction method using a pattern area density map*, J. Vac. Sci. Technol. B 10 (6), Nov/Dec. 1992; pp. 3072-3076

EXAMINER

DATE CONSIDERED



K F *1-29-01*

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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